

**Notice of References Cited**

Application No.

Applicant(s)

John R. Leitz

Examiner

Group Art Unit

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**U.S. PATENT DOCUMENTS**

	DOCUMENT NO.	DATE	NAME	CLASS	SUBCLASS
A					
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01/31/01**FOREIGN PATENT DOCUMENTS**

	DOCUMENT NO.	DATE	COUNTRY	NAME	CLASS	SUBCLASS
N						
O						
P						
Q						
R						
S						
T						

**NON-PATENT DOCUMENTS**

	DOCUMENT (Including Author, Title, Source, and Pertinent Pages)	DATE
U	A Survey of Ion Beam Milling Techniques for Piezoelectric Device Fabrication, by R. N. Castellano et al, Proceeding of the 29th Annual Symposium on Frequency Control, pages 128 through 134	1975
V		
W		